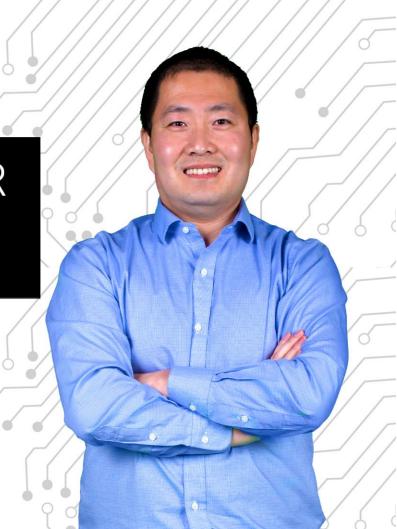


HIGH VOLTAGE SEMINAR WEI ZHANG ISOLATED GATE DRIVERS

ISOLATED GATE DRIVER 101: FROM INSULATION SPEC TO END EQUIPMENT REQUIREMENTS

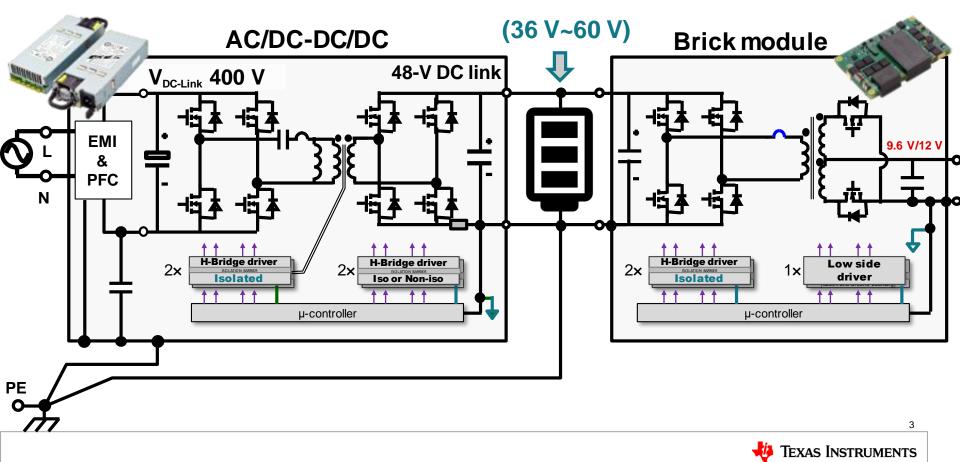


Agenda

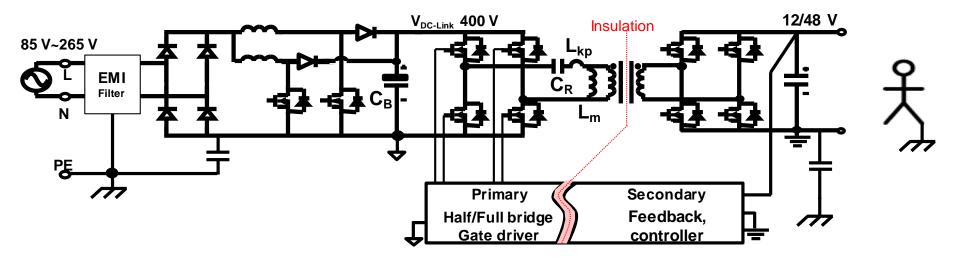
- Isolated gate driver fundamentals
- Insulation specification and verification
- Requirements of isolated gate drivers in popular applications
- Questions



Isolated driver in server/telecom



Why is isolation required?



- 1. Power delivery $-V_1/V_2 = N_1/N_2$
- 2. Signal Communication
- 3. Safety

- 4. Breaking ground loop CM noise
- 5. High voltage >800 V
- 6. Performance: high CMTI



Types of isolation methods in gate drivers

Technology	Advantages	Simplified diagram
Optical	Long historyLow emissions	
Inductive	 High speed data Low power CMTI Low ch-ch skew High temp 	
Capacitive	 High speed data Low power CMTI Low channel-channel skew High temp High working voltage 	



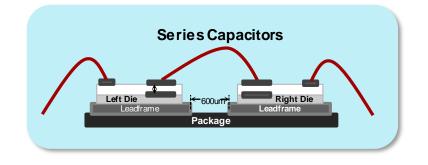
Types of isolation grades

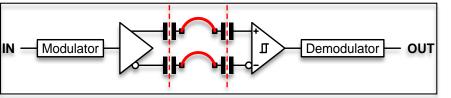
- Functional isolation
 - For protecting circuits
 - → Gnd bounce, high voltage, transient between secondary circuits
- Basic isolation
 - Single level of isolation to protect against electric shock
- Supplementary isolation
 - Independent insulation if single level fails
- Double isolation
 - Basic + Supplementary → For human safety which requires redundancy
- Reinforced isolation
 - A single insulation system that provides same ratings as double insulation



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An example: reinforced capacitive isolation





- Reinforced isolation is realized by thick SiO₂ capacitors combined in series

 Each channel uses high voltage isolation capacitors on both die
- Combined isolation capacitor thickness is >21 um
- 12.8 kV_{PK} surge voltage, 8 kV_{PK} transient over-voltage, 1.5 kV_{RMS} working voltage

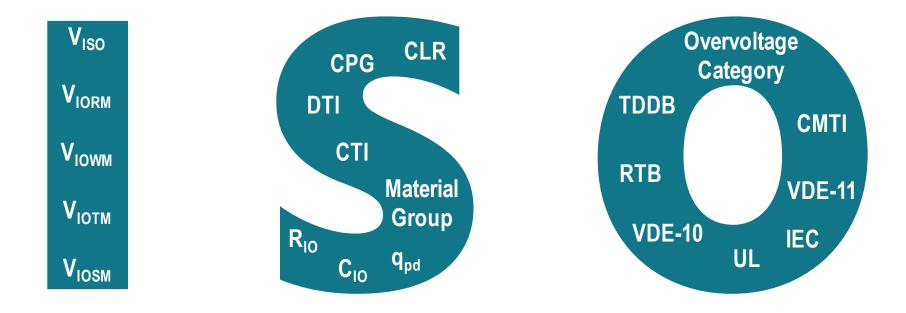


Example: insulation spec. of an isolated gate driver

(6.6 Ins	sulation	Specifi	cations		IEC/EN/DIN EN 60747-5-5 nsulation Characteristics	* (Optio	
		PAR	AMETER	\wedge	TEST CONDITIONS			
	CLR	CLR External clearance ⁽¹⁾ Shortest pin		-to-pin distance through air	Deviption	Symbol		
	CPG	Exte		de ⁽¹⁾ Shortest pin	-to-pin distance across the pa		Symbol	
ľ				V 0884-11 VDE V 0884-11): 201	7-01 ⁽²⁾			
	DTI	Dista	V _{IORM}	Maximum repetitive peak isolation voltage	AC voltage (bipolar)	Installation classification per DIN VDE 0110/39, Table 1 for rated mains voltage ≤ 150V _{RMS}		
	СТІ	Com		Maximum working isolation	AC voltage (sine wave); time deper	for rated mains voltage $\leq 300V_{RMS}$		
		Mate	V _{IOWM}	voltage	(TDDB), test (See Figure 1)	for rated mains voltage \leq 450V _{RMS}		
		Over			DC voltage	for rated mains voltage $\leq 600V_{RMS}$ for rated mains voltage $\leq 1000V_{RMS}$	•	
		IEC VIOTM Maximum transient iso		Maximum transient isolation voltage	$V_{TEST} = V_{IOTM}$, t = 60 sec (qualificate V_{TEST} = 1.2 × V_{IOTM}, t = 1 s (100%)	Climatic Classification		
			V _{IOSM}	Maximum surge isolation voltage ⁽³⁾	Test method per IEC 62368-1, 1.2/ V _{TEST} = 1.6 × V _{IOSM} = 12800 V _{PK} (0	Pollution Degree (DIN VDE 0110/39)		
		Pollu			Method a, After Input/Output safety	Maximum Working Insulation Voltage		
				$V_{ini} = V_{IOTM}$, $t_{ini} = 60s$; $V_{pd(m)} = 1.2 \times V_{IORM} = 2545 V_{PK}$, t_n	Input to Output Test Voltage, Method b* V _{IORM} × 1.875 = V _{PR} , 100% Production Test with t _m =1 sec, Partial discharge < 5 pC	V _{PR}		
	UL 1577	With	q _{pd}	Apparent charge ⁽⁴⁾	Method a, After environmental tests $V_{ini} = V_{IOTM}$, $t_{ini} = 60s$; $V_{pd(m)} = 1.6 \times V_{IORM} = 3394 V_{PK}$, t_{n}	Input to Output Test Voltage, Method a* V _{IORM} × 1.6 = V _{PR} , Type and Sample Test, t _m =10 sec, Partial discharge < 5 pC	V _{PR}	
	V _{ISO}	vvitn			Method b1; At routine test preconditioning (type test)	Highest Allowable Overvoltage* (Transient Overvoltage t _{ini} = 60 sec)	VIOTM	
İ.					$V_{ini} = 1.2 \times V_{IOTM}$; $t_{ini} = 1s$;	Safety-limiting values – maximum values allowed in the event of a failure		
F		Linh In			$V_{pd(m)} = 1.875 * V_{IORM} = 3977 V_{PK}$,	Case Temperature	Ts	
	CM _H	High-le immuni		Barrier capacitance, input to output ⁽⁵⁾	V _{IO} = 0.4 sin (2πft), f =1 MHz	Input Current	Is, INPUT	
ŗ		Low-lev			V _{IO} = 500 V at T _A = 25°C	Output Power	Ps, output	
	CML immuni		R _{IO}	Isolation resistance, input to output ⁽⁵⁾	$V_{IO} = 500 \text{ V} \text{ at } 100^{\circ}\text{C} \le \text{T}_{A} \le 125^{\circ}\text{C}$	Insulation Resistance at T_S , $V_{IO} = 500V$	Rs	
-	/			oupur	V _{IO} = 500 V at T _S =150°C	210	<u>`</u>	



Terminologies





What is the purpose?

□ **<u>Capability verification</u>** for basic, supplementary and reinforced insulation barrier

to withstand

- 1. <u>Electrical</u> stresses
- 2. <u>Mechanical</u> stresses

as well as

3. <u>Thermal</u> and <u>environmental</u> influences

which may occur during the anticipated life of the equipment



Standards – a broad categorization

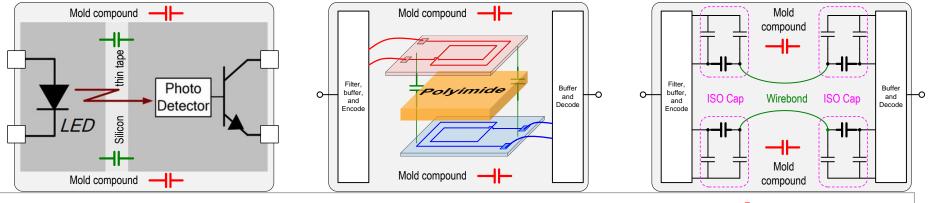
Category	Standards	Coverage	Terminologies
	IEC 60747-5-5 (VDE 0884-5-5)	Opto-couplers only	$R_{IO}/C_{IO}, V_{ISO}/V_{IOTM}, V_{IORM},$
Component	IEC60747-17 (release soon)	Magnetic and capacitive coupler	V _{IOSM} , V _{IOWM} , CMTI, q _{pd} , CTI,
standard	VDE 0884-10, -11		Above spec " $-V_{ISO}$, +TDDB"
	UL 1577	Opto-couplers & digital isolator	V _{ISO}
	IEC 60601-1	Medical equipment	
Equipment standard	IEC 61010-1	Measurement, control and lab	
	IEC 60950-1 & IEC 62368-1	Information Technology up to 600 V	CLR, CPG, Pollution Degree,
Supporting standard	IEC 60664-1	Insulation coordination for low- voltage systems	Material Group, Over voltage category



R_{IO}, C_{IO}

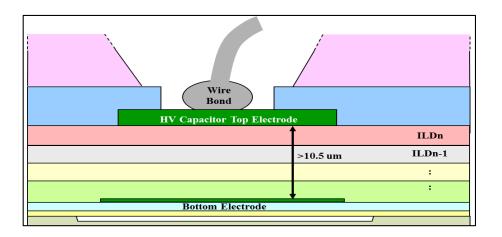
- □ C_{IO} Input-to-output capacitance
 - The total capacitance between all input terminals connected together and all output terminals connected together
 - $F = 1 \text{ MHz}, I_F = 0, I_C = 0, V_{IO} = 0.4 \sin(\omega t)$
 - Capacitance meter
 - Resistance meter (V_{IO}=500 V)

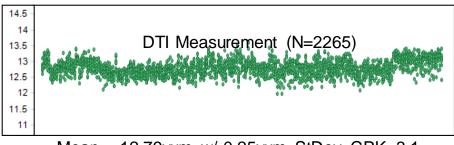
Temp	Requirement
T _{amb}	>10 ¹² Ω
T _{amb.max}	>10 ¹¹ Ω
Ts	>10 ⁹ Ω





DTI: Distance Through Insulation





Mean = 12.79vum w/ 0.25vum StDev, CPK=3.1

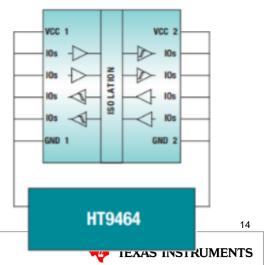
- Thickness is directly related to breakdown voltage
- Reinforced barrier consists of two high voltage capacitors
 - HV Caps on each die
- □ Each capacitor has a thick SiO_2 dielectric > 10.5 µm



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V_{ISO}, V_{IOTM:} isolation withstand voltage

- \Box V_{ISO} Maximum withstanding isolation a.c. (r.m.s.) voltage for 1 min
 - UL1577 specifies test either using DC or AC voltage source
- \Box V_{IOTM} Maximum transient isolation voltage (A peak value) = 1.414 × V_{ISO}
 - Purpose verify the ability of the device to withstand the isolation test voltage under specified conditions for a short period, i.e. arcing, load change
 - AC voltage with commercial frequency for 1 min
 - Routine test
 - IEC: 1 s or 2 s is at 100% or maximum 120% of 1 min rating
 - UL: 1 s at ≥120%
 - T_A=25 °C
 - Requirements
 - Ext. or int. flash-over shall not occur during the test
 - Shall pass the post-test measurements



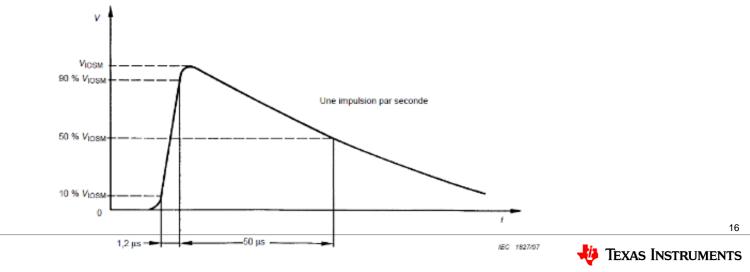
V_{IOWM} and V_{IORM}

- \Box V_{IOWM} Maximum working isolation voltage
 - Characterizing the specified long term or the working voltage withstand capability of the isolation
 - r.m.s voltage includes equivalent d.c. voltage
- VIDRM Maximum repetitive peak isolation voltage
 - A repetitive peak value of withstand voltage, characterizing the specified withstand capability of its isolation against repetitive peak voltages
 - V_{IORM} = 1.414 × V_{IOWM} for most datasheets
 - The degradation of the galvanic isolation depends normally on the peak voltage,
 V_{IORM} is the repetitive peak value of the absolute envelop voltage over time.



V_{IOSM}

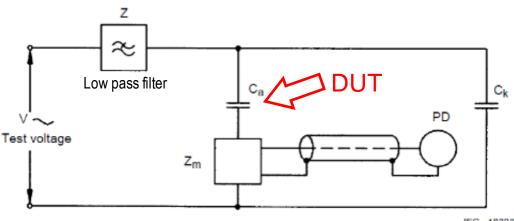
- VIDSM Maximum surge isolation voltage <u>(type test only)</u>
 - The highest instantons value of an isolation voltage pulse with short time duration and of specified wave shape
 - Goal: Verifies the DUT's immunity to very high voltage levels over a short period of time, e.g. lightening strike
 - One pulse per second, 50 consecutive surge pulses



Q_{pd}: apparent charge caused by partial discharge

- An electric discharge that only partially bridge the insulation between conductors
- □ Goal to verify the performance of insulation between input and output of a insulator by measuring the partial discharge level under specified conditions

□ Requirement: <5 pC



Term	Meanings
Са	Device under test, modeled as a capacitor
Ck	Bypassing capacitor
Zm	Measuring circuit (impedance, surge limit, others)
PD	Partial discharge measuring instrument

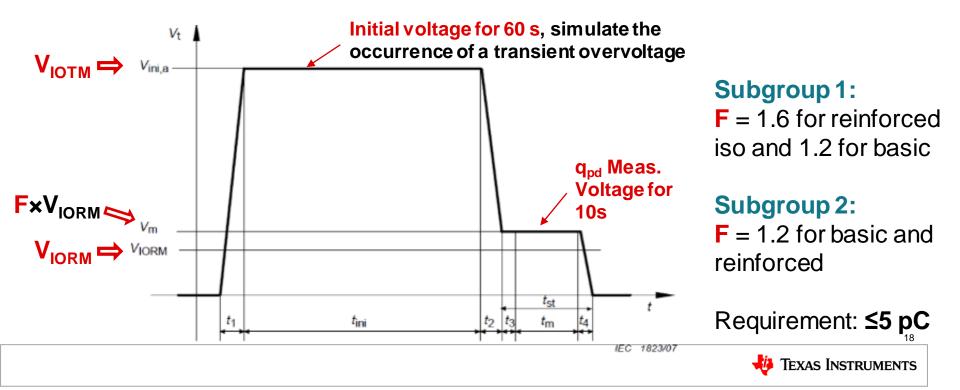


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q_{pd} test: method a), type test

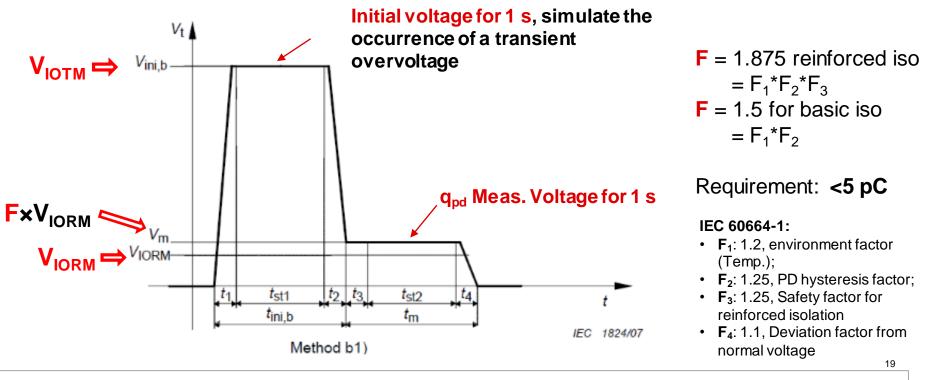
□ Sample tested – Must Be Tested From Random Production Lot Once / Quarter

□ No failures, Perform if new package material, lead frame, package construction.



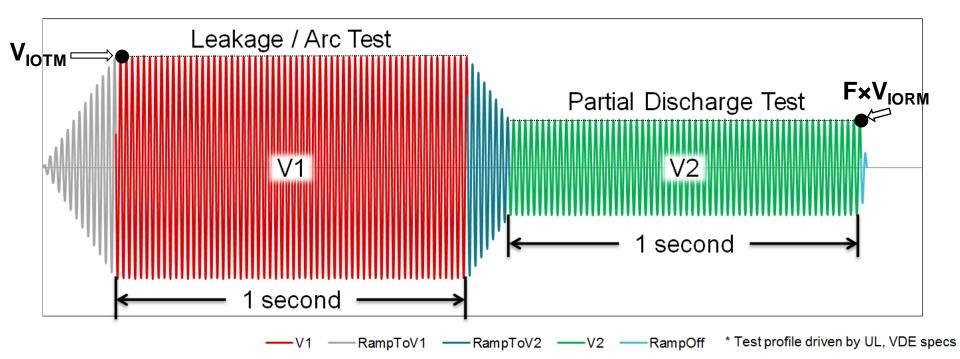
q_{pd} test: method b1), routine test

Routine tested





q_{pd} test: method b1), an example waveform

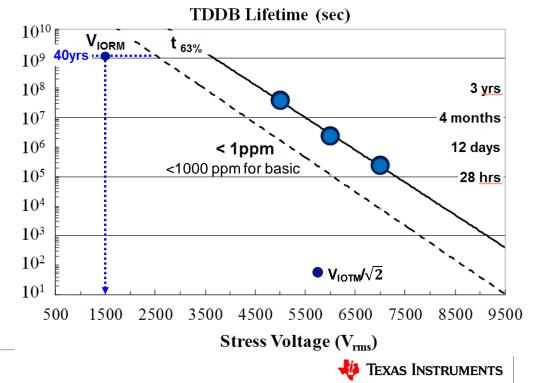




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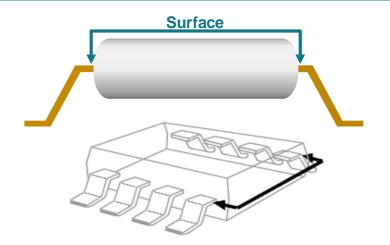
TDDB: Time Dependent Dielectric Breakdown

- Aging affect observed in isolators using SiO₂ or silica based materials to provide internal solid insulation
- Accelerated lifetime testing of the isolation barrier
 - Weibull statistics at each voltage
 - □ Multiple voltages, fit to model
 - $L=c\cdot e^{-k\cdot V^{-n}}$
 - L time to failure;<2 $M\Omega$ at 500 V_{DC} for basic <4 $M\Omega$ at 500 V_{DC} for reinforced V is test voltage c, n, k are constant

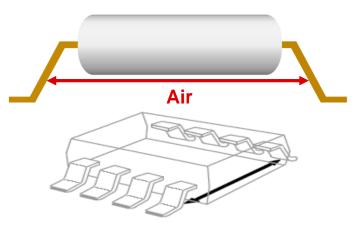


CPG and CLR

Creepage distance (CPG)



Clearance distance (CLR)



Shortest distance **along the surface** of a solid insulating material between two conductive parts

Pollution, humidity, condensation matters most Shortest distance **in air** between two conductive parts

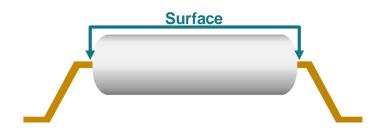
Air pressure (altitude), temperature matters most



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CPG and CLR

Creepage distance (CPG)



Clearance distance (CLR)



- Dimensioned for a giving 1) RMS working voltage, 2) pollution degree,
 3) material group,
- No flashover or breakdown of insulation will occur

- Dimensioned for the likelihood of breakdown due to 1) temporary voltage, 2) transient voltages, 3) recurring peak voltages
- □ Multiplication factor above 2000 m

□ ×1.48 @5000 m



Material group and CTI

- □ Material groups depend on the comparative tracking index (CTI)
- □ CTI the maximum voltage V_{AC} (in Volts) at which an insulating material withstands 50 drops (per 30 s) of contaminated water (0.1% ammonium chloride)
 - □ No tracking (<0.5 A) (formation of conductive paths)
 - An accelerated simulation of conditions of surface in equipment using insulating material

Material groups	CTIrange	
Material group I	CTI ≥ 600	
Material group II	400 ≤ CTI < 600	
Material group IIIa	175 ≤ CTI < 400	
Material group IIIb	100 ≤ CTI < 175	If not specified
* Material group is verified by e	evaluation of the test data according to IEC 60112	



Pollution Degree

Classes	Descriptions	Examples
Pollution degree 1	 There is no pollution or only dry, non- conductive pollution 	• Sealed components, equipment or subassemblies
Pollution degree 2	 Temporarily become conductive due to occasional condensation 	• IEC 60950/62368 • Lab, office
Pollution degree 3	 Subject to conductive pollution Non-conductive pollution that could become conductive due to expected condensation 	 Industrial and farming
Pollution degree 4	 Continuous conductivity occurs due to conductive dust, rain or other wet conditions 	 Outdoor applications



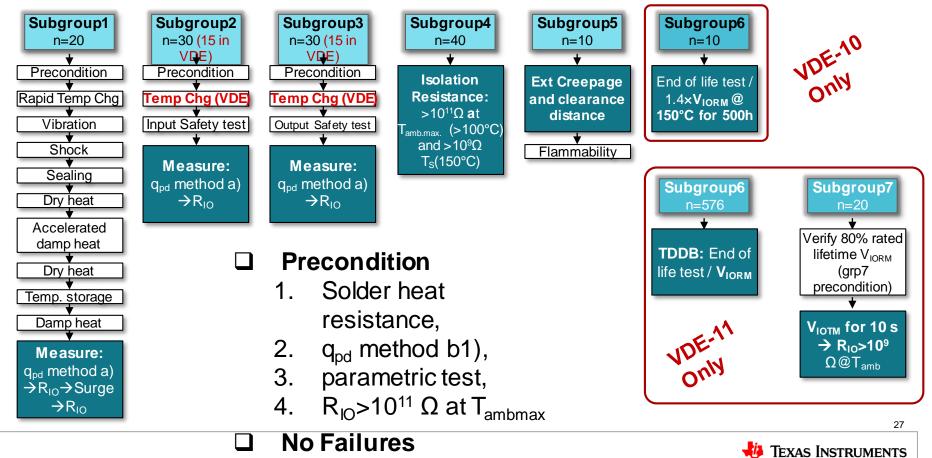
Impulse withstand voltage or overvoltage category

- □ A probabilistic implication used for equipment energized directly from low voltage mains
- □ Over voltage category ← synonymous → Impulse withstand category

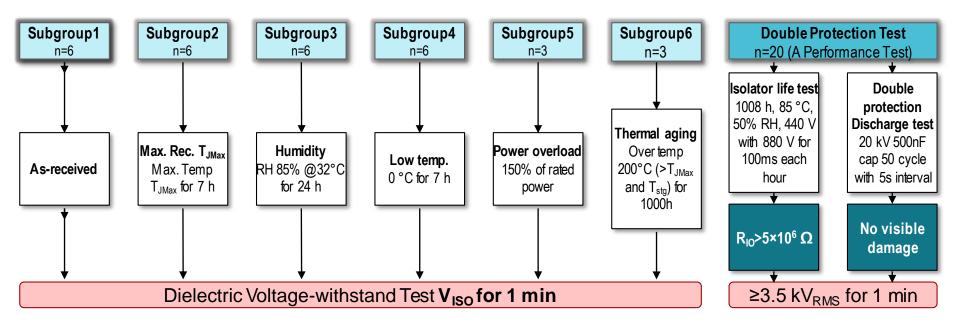
Categories	Descriptions	Examples
CAT. 4	Original of installation	Electricity metersUtility transformers
CAT. 3	 Fixed installation where reliability and availability is subject to special requirements 	Utility panelDistribution board
CAT. 2	 Energy consuming equipment supplied from fixed installation 	Outlets10m away from III
CAT. 1	 Equipment for connection to circuit in which measures are taken to limit transient voltage to a low level 	Thermostat,Office printer
		•



IEC60747-5-5 and VDE 0884-10 and -11 type tests



UL 1577 type tests



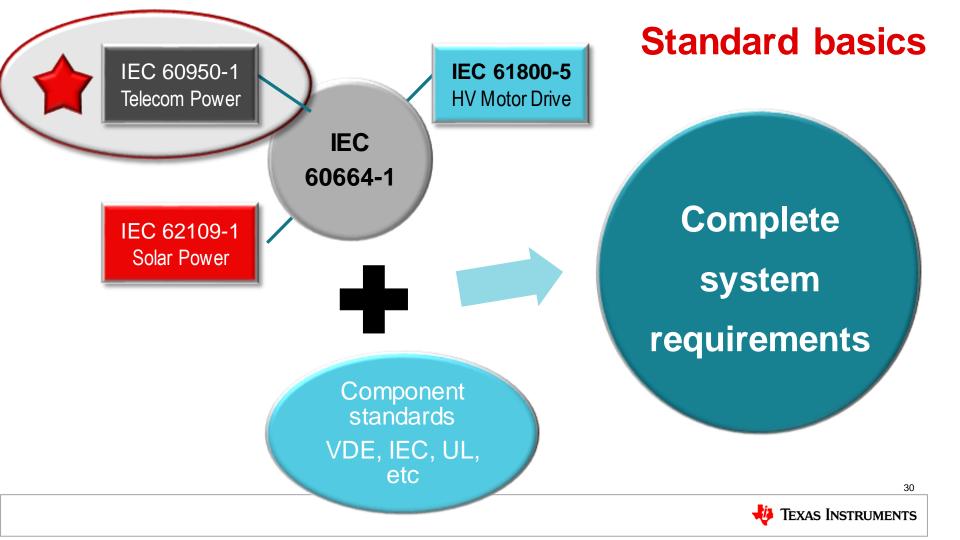
No Isolation Breakdown



Device standards comparison (UL, IEC, VDE)

Reinforced ISO		UL 1577	IEC60747-5-5	VDE 0884-10	VDE 0884-11 (new)	
Туре		Opto-couplers or digital isolator	Opto-couplers	Magnetic and capacitive coupler		
Production Test q _{pd}		$1.2 \times V_{ISO}$ for 1 s	1.0× or 1.2×V _{ISO} for 1 s or 2 s	Not specified		
		Not specified	1.875×V _{IORM} for 1 s	1.875×V _{IORM} for 1 s		
V _{IOWM}		Not specified	Based on q _{pd} test No TDDB	No TDDB submission required	TDDB (T _A &T _{JMAX} , 3lots, 3 data points differ by 2 orders of magnitude)	
Min Rate Lifetime @ V _{IOWM}		Not specified	Not specified	No specified	37.5 years w 20% margin	
Life Verification		1008 h, 85°C T _A , RH ≤50%, 440 Vac (w/ 0.1s 880Vac per h)	No specified	500h at 1.4×V _{IORM} at 80% rated lifetime + V 150 °C 10 s + R _{IO}		
Surge	l	Not specified	V _{IOSM} , min. 10kV	1.6×V _{IORM} , min. 10 kV		





What is IEC 60664-1 about?

□ Insulation coordination for equipment within low-voltage systems

- Up to 1000 $V_{a.c}$ (<30 kHz) or
- $-~1500~V_{d.c}$
- 1. Clearance, creepage distance
- 2. Electric strength testing



Highlights from IEC 60664-1

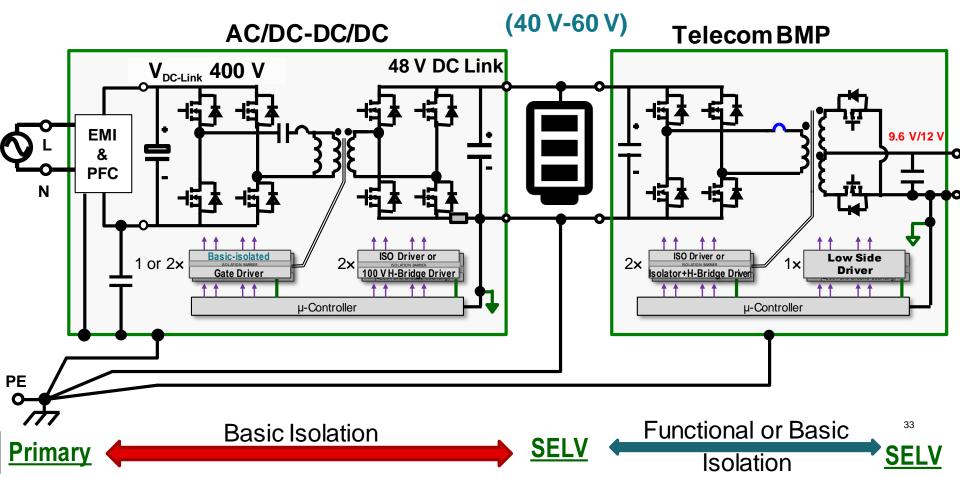
- Table F.1 Rated impulse voltage for equipment powered directly by low voltage mains
- □ Table F.2 Dimensioning CLR to withstand transient voltage
 - Basic insulation follows Table F.2 directly
 - Reinforced insulation follows Table F.2 but one step higher →
 - ➤ 330 V, 500 V, 800 V, 1 500 V, 2 500 V, 4 000 V, 6 000 V, 8 000 V, 12 000 V.
- □ Table F.4 Dimensioning CPG to avoid failure due to tracking
- □ Table A.2 Altitude correction factors above 2000 m for CLR

Electric strength test

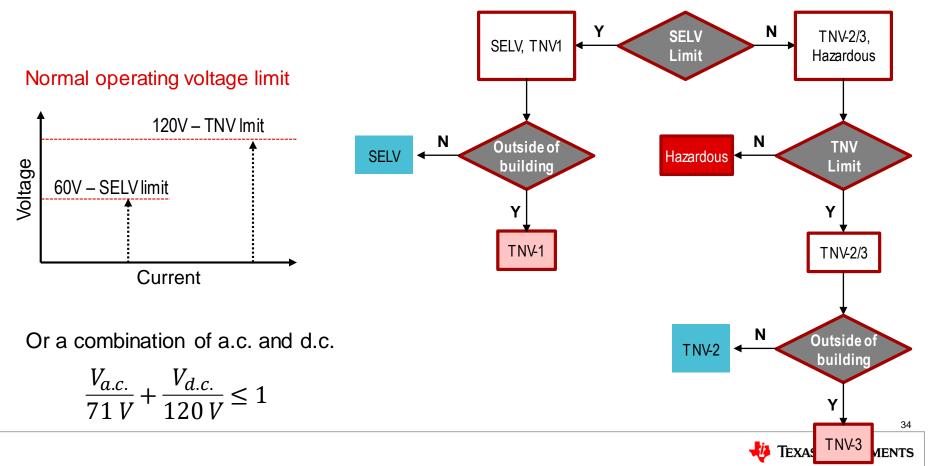
- □ Impulse withstand voltage, or
- Partial discharge based on working voltage



Telecom AC-DC with 36 V-60 V output

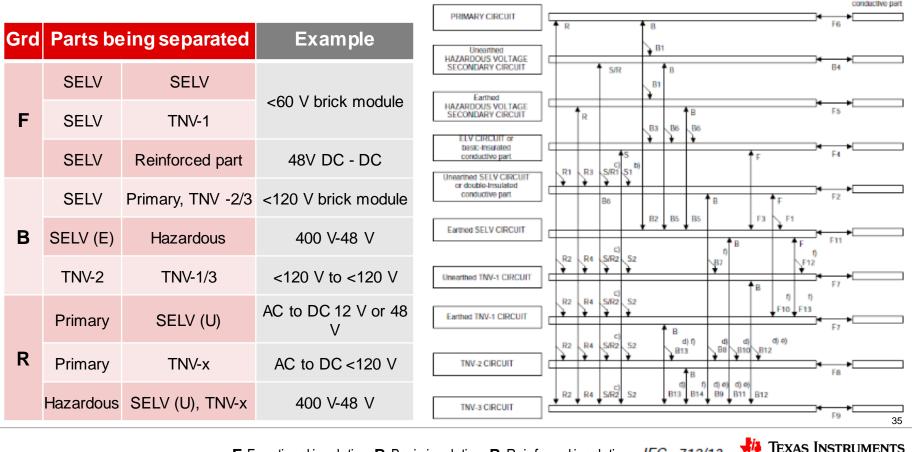


What is SELV and TNV?



Insulation grades: CLR, CPG, electrical strength, etc.

Similar circuit or



F-Functional insulation; B-Basic insulation; R-Reinforced insulation IEC 712/13

Mains transient voltage: clearance distance

□ Transient voltage from AC mains

	AC MAINS SUPPLY voltage ^a (line to neutral voltage)	MAINS TRANSIENT VOLTAGE ^b V peak					
	V r.m.s.		Overvoltage Category				
		I	Ш	III	IV		
	up to and including 50	330	500	800	1 500		
	over 50	500	800	1 500	2 500		
	over 100 Including 120/208 V, 120/240 V	800	1 500	2 500	4 000		
	over 150 Including 230/400 V, 277/480 V	1 500	2 500	4 000	<mark>6</mark> 000		
	over 300 Including 400/690 V	2 500	4 000	6 000	8 000		

* IEC 60950-1 Ed2, Table 2J – AC mains transient voltage

□ IEC 62368-1:500 V_{PK} for DC power distribution system earthed at a single point, or 350 V_{PK} earthed at the source (5.4.2.3.2.3)



Minimum clearances: primary circuits

➢ In primary circuits and between primary to secondary (mm), 2000m

	Mains transient						
Peak working voltage	1500V			2500V			
(V _{РК})	F	В	R	F	В	R	
71 V	0.4	1.0	2.0	1.0			
210 V	0.5	(0.5)	(1.0)	1.4	2.0	4.0	
420 V	1.5	2.0 (0.5)	4.0 (1.0)	1.5	(1.5)	(3.0)	

Value in parentheses applies based on IEC 62368-1

Table 2K, IEC 60950-1 Ed2 Amd1,

Altitude: 2000m. For 5000m, multiplication factor is 1.48



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Minimum clearances: secondary circuits

> Clearance in **secondary circuits (mm)**, 2000m

	Mains transient						
Peak working voltage (V _{PK})	1500 V			2500 V			
(* PK)	F	В	R	F	В	R	
71 V							
140 V	0.5	1.0	2.0	1.5	2.0	4.0	
210 V							

Table 2M, IEC 60950-1 Ed2

Altitude: 2000m. For 5000m, multiplication factor is 1.48



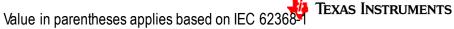
Creepage distance

Creepage distance (CPG)

- Dimensioned for a giving 1) RMS working voltage, 2) pollution degree,
 3) material group,
- No flashover or breakdown of insulation will occur

*Pollution degree 2

	RMS working voltage (V)	Material group		
Isolation grade		I	II	Ш
Functional or basic isolation	80	0.67	0.9 (0.95)	1.3
	125	0.75	1.05	1.5
	400	2.0	2.8	4.0
Reinforced isolation	80	2 × distance above		
	125			
	400			



DTI & electric strength

- No minimum DTI is required semiconductor device which is completely filled with insulation compound (semiconductor device), provided passing
 - 1) Electric strength **TYPE** test

AND

- 2) Electric strength ROUTINE test (insulation grade matters)
 - A. Basic and reinforced isolation (5.2.2)
 - **Peak working voltage** *Table 2B*; OR
 - **Required withstand voltage** *Table* 5C(CAT III shall use Table 5C)
 - B. Functional isolation (5.3.4)
 - Same with above if CPG&CLR is NOT met (< 707 V required withstand voltage when working voltage < 60V_{DC})
 OR
 - NOT required if CPG&CLR is met



Electric strength test B: based on required withstand voltage

IEC 60950-1 ed. 2.0, Table 5C, Amd2,

		Test voltage for electric strength based on required withstand voltage		
	Required withstand voltage kV _{РК}	Functional or Basic (kV _{PK} or d.c.)	Reinforced insulation (kV _{PK} or d.c.)	
	0.8	0.9 (0.8)	1.5	
	1.5	1.5	2.5	
⇒	2.5	2.5	4.0	
	4.0	4.0	6.0	

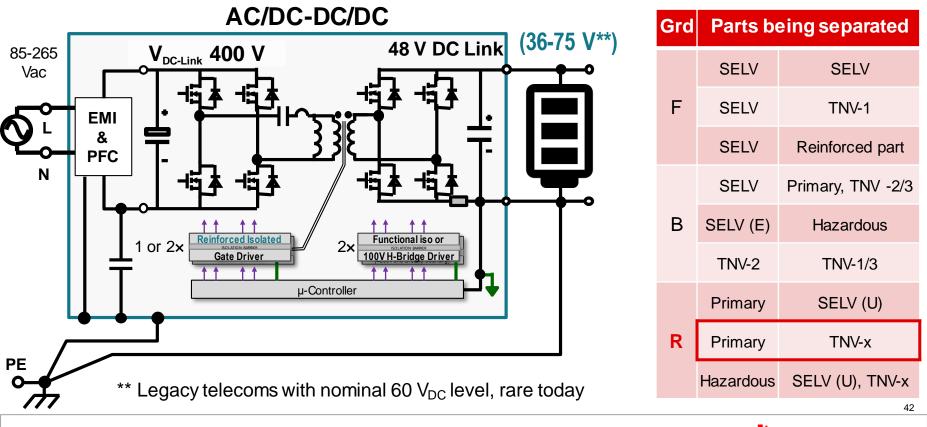
CAT III shall use Table 5C

Value in parentheses applies based on IEC 62368-1

Routine test allows test duration reduced to 1s, and test voltage (for Table 5C) reduced by 10%

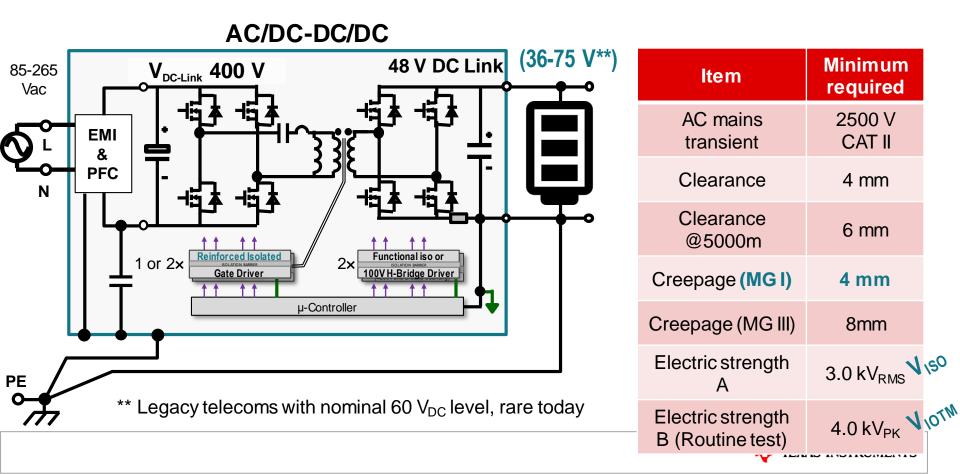


Case study 1b: isolated AC/DC (TNV-x)





Case study 1b: isolated AC/DC (TNV-x)



Questions?





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